

- **Test strategy**
 - Scope (what will be tested and how)
 - Output Groups
 - Distribution of similarity scores
 - Silhouette scores
 - Types of tests to be used
 - Output groups
 - Visual confirmation of similar wafers
 - *Expert user testing*
 - Distribution of similarity scores
 - Count number of wafers in each group
 - Ensuring that groups do not have an overwhelming number of wafers
 - Ensure one or more wafers are not similar to every other wafer
 - Silhouette scores
 - Ensure acceptable value
- **Specific tests and criteria for acceptance**
 - Output groups
 - No wafers in a group that do not match patterns of fails of other wafers in group
 - Distribution of similarity scores
 - No over-sized groups
 - Silhouette Scores
 - >0.5
- **Testing schedule and resources.**
 - After every run of the model on new data or after a change and re-run.
 - Resources
 - Output Log
 - Wafer graphing functions
 - Grouping functions to turn high similarity scores into groups/clusters of high similarity
- **The quality behaviors your team uses to enhance system quality**
 - Consistent testing
 - Logged results
 - Detailed graphing of wafers